



JPW

PATENT APPLICATION  
PO-8734  
BTS054034

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

APPLICATION OF )  
MARKUS HAIML ET AL )  
SERIAL NUMBER: 10/565,909 )  
DATE SUBMITTED: JANUARY 25, 2006 )  
TITLE: ANALYTICAL SYSTEM, AND )  
METHOD FOR ANALYZING )  
NONLINEAR OPTICAL SIGNALS )

**INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. 1.97(b)**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This disclosure statement under 37 CFR 1.97 & 1.98 is submitted before the first Office Action in order that the Patent and Trademark Office may consider the relevancy of certain information to the invention described and claimed in the subject application, and in compliance with the regulations concerning information disclosure statements. Copies of the foreign documents and articles listed on the attached Form PTO-1449 are enclosed.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an enveloped addressed to: Commissioner for Patents, Alexandria, VA 22313-1450 on 9/20/06

Date

Aron Preis, Reg. No. 29-426

Name of applicant, assignee or Registered Representative

Signature

September 20, 2006

Date

Concise statements of the presently understood relevance of each of the documents are found in the specification filed.

This Information Disclosure Statement should not be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, that any document mentioned herein constitutes prior art, or that the documents listed severally or in any combination with one another or with any other information, are believed to render any claim in the subject application prima facie unpatentable.

Respectfully submitted,

By



Aron Preis  
Attorney for Applicant(s)  
Reg. No. 29,426

Bayer MaterialScience LLC  
100 Bayer Road  
Pittsburgh, Pennsylvania 15205-9741  
(412) 777-3814  
FACSIMILE PHONE NUMBER  
(412)777-3902  
s:\bsh\AP2005

Form PTO 1449 Rev. 7-80	U.S. Department of Commerce Patent and Trademark Office	Atty. Docket No. PO8734/BTS054034	Serial No. 10/565,909
LIST OF PRIOR ART CITED BY APPLICANT (Use Several Sheets If Necessary)		Applicant Markus Haiml et al	
		Filing Date January 25, 2006	Group No.

SEP 22 2006

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		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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	AB	**5,034,613	07/23/91	Denk et al	250	458.1	
	AC	5,445,934	08/29/95	Fodor et al	435	6	
	AD	**5,459,574	10/17/95	Lee et al	356	437	
	AE	5,742,355	04/21/98	(Bel. to corresp. to WO De Haan et al	96/15625) 348	607	
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							Yes	No*
	AL	95/33197 A1	12/07/95	World				
	AM	01/13096 A1	02/22/01	World				X
	AN	02/46756 A1	06/13/02	World				X
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	AR	Science, 248, April 6, 1990, pages 73-76, Winfried Denk et al, "Two-Photon Laser Scanning Fluorescence Microscopy"
	AS	Applied Physics, B, 73 (month unavailable) 1990, pages 869-871, G.L. Duveneck et al, "Evanescent-field-induced two-photon fluorescence: excitation of macroscopic areas of planar waveguides"
	AT	Analytica Chimica Acta, 469, (month unavailable) 2002, pages 49-61, Gert L. Duveneck et al, "Planar waveguides for ultra-high sensitivity of the analysis of nucleic acids"

EXAMINER

DATE CONSIDERED

EXAMINER Initial if references considered, whether or not citation is in conformance with MPEP 609: Draw line through if not in conformance and not considered. Include copy of this form with next communication to applicant.

- \* Neither English Language Equivalent nor an English Language Translation is available.  
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<b>Form PTO 1449</b> Rev. 7-80 <b>U.S. Department of Commerce</b> <b>Patent and Trademark Office</b> <b>LIST OF PRIOR ART CITED BY APPLICANT</b> (Use Several Sheets If Necessary)	Atty. Docket No.	Serial No.
	PO8734/BTS054034	10/565,909
	Applicant	
	Markus Haiml et al	
	Filing Date	Group No.
	January 25, 2006	

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	AE	6,961,490 B2	11/01/05	(Bel. to corresp. to WO Maisenhoelder et al	01/55691) 385	37	
	AF	7,060,957 B2	06/13/06	(Bel. to corresp. to WO Lange et al	01/84182) 250	208.1	
	AG	2001/0001021 A1	05/10/01	(Bel. to corresp. to WO Kraus et al	98/22799) 385	12	
	AH	2002/0076154 A1	06/20/02	(Bel. to corresp. to WO Maisenhoelder et al	01/55691) 385	37	
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	AR	Peregrinus, 232, (month unavailable) 1983, pages 1-30, M.L. Meade, "Lock in amplifiers: principles in applications"
	AS	IEEE Journal of Quantum Electronics, Vol. 31, No. 9, September 1995, pages 1705-1708, T. Spirig et al, "The Lock-In CCD-Two-Dimensional Synchronous Detection of Light"
	AT	IEEE Transactions of Electron Devices, Vol. 44, No. 10, October 1997, pages 1643-1647, Thomas Spirig et al, "The Multitap Lock-In CCD with Offset Subtraction"
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	Applicant <b>Markus Haiml et al</b>	
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	AA	2003/0148542 A1	08/07/03	(Bel. to corresp. to WO Pawlak et al	01/92870) 436	518	
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	AI						
	AJ						
	AK						

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							Yes	No*
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**OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

	AR	J. Opt. Soc. Am. A, Vol. 18, No. 8, August 2001, pages 1972-1979, Arnaud Dubois, "Phase-map measurements by interferometry with sinusoidal phase modulation and four integrating buckets"
	AS	Applied Optics, Vol. 41, No. 4, February 2002, pages 805-812, Arnaud Dubois et al.
		***"High-resolution full-field optical coherence tomography with a Linnik microscope"
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		Proceedings of the Spie – The International Society for Optical Engineering Spie-Int. Soc. Opt. Eng. USA, Bd. 4633, 23 Januar 2002 (2002-01-23) Seiten 50-61, XP001203516

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